

Search Notes

Application/Control No.

10/750,864

Examiner

Queenie Dehghan

Applicant(s)/Patent under
Reexamination

HIRANO ET AL.

Art Unit

1731

SEARCHED

Class	Subclass	Date	Examiner
65	412,419, 424-426 428	4/13/2007	QSD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR